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74F843

9-Bit Transparent Latch

General Description

The 74F843 bus interface latch is designed to eliminate the extra packages required to buffer existing latches and provide extra data width for wider address/data paths or buses carrying parity.

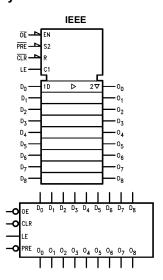
Features

■ 3-STATE output

Ordering Code:

Order Number	Package Number	Package Description
74F843SCX	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I _{IH} /I _{IL}	
Pin Names	Description	HIGH/LOW	Output I_{OH}/I_{OL}	
D ₀ –D ₈	Data Inputs	1.0/1.0	20 μA/-0.6 mA	
ŌĒ	Output Enable Input	1.0/1.0	$20~\mu\text{A}/\!\!-\!\!0.6~\text{mA}$	
LE	Latch Enable	1.0/1.0	20 μA/-0.6 mA	
CLR	Clear	1.0/1.0	20 μA/-0.6 mA	
PRE	Preset	1.0/1.0	20 μA/-0.6 mA	
O ₀ –O ₈	3-STATE Data Outputs	150/40	−3 mA/24 mA	

Functional Description

The 74F843 consists of nine D-type latches with 3-STATE outputs. The flip-flops appear transparent to the data when Latch Enable (LE) is HIGH. This allows asynchronous operation, as the output transition follows the data in transition. On the LE HIGH-to-LOW transition, the data that meets the setup times is latched. Data appears on the bus when the Output Enable (\overline{OE}) is LOW. When \overline{OE} is HIGH, the bus output is in the high impedance state. In addition to the LE and $\overline{\text{OE}}$ pins, the 74F843 has a Clear ($\overline{\text{CLR}}$) pin and a Preset ($\overline{\text{PRE}}$). These pins are ideal for parity bus interfacing in high performance systems. When $\overline{\text{CLR}}$ is LOW, the outputs are LOW if $\overline{\text{OE}}$ is LOW. When $\overline{\text{CLR}}$ is HIGH, data can be entered into the latch. When $\overline{\text{PRE}}$ is LOW, the Outputs are HIGH if OE is LOW. Preset overrides CLR.

Function Table

Inputs					Internal	Output	Function
CLR	PRE	OE	LE	D	Q	0	runction
Н	Н	Χ	Х	Χ	Х	Z	High Z
Н	Н	Н	Н	L	L	Z	High Z
Н	Н	Н	Н	Н	Н	Z	High Z
Н	Н	Н	L	Χ	NC	Z	Latched
Н	Н	L	Н	L	L	L	Transparent
Н	Н	L	Н	Н	Н	Н	Transparent
Н	Н	L	L	Χ	NC	NC	Latched
Н	L	L	Χ	X	Н	Н	Preset
L	Н	L	Χ	Χ	L	L	Clear
L	L	L	Χ	Χ	Н	Н	Preset
L	Н	Н	L	Χ	L	Z	Latched
Н	L	Н	L	Χ	Н	Z	Latched

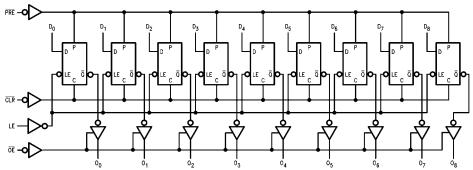
H = HIGH Voltage Level

L = LOW Voltage Level

X = Immaterial

Z = High Impedance NC = No Change

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C

-55°C to +150°C Junction Temperature under Bias V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V-0.5V to +7.0V

Input Voltage (Note 2) Input Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC}

3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

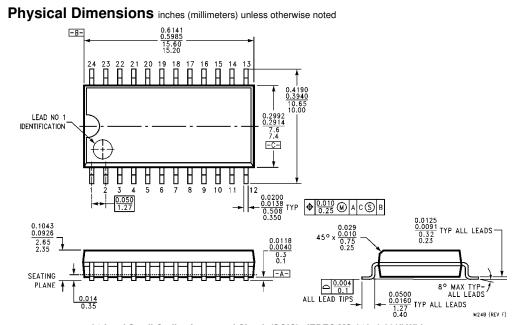
Symbol	Parameter		Min	Тур	Max	Units	v _{cc}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	$I_{IN} = -18 \text{ mA}$
V _{OH}	Output HIGH	10% V _{CC}	2.5					$I_{OH} = -1 \text{ mA}$
	Voltage	10% V _{CC}	2.4			V	Min	$I_{OH} = -3 \text{ mA}$
		5% V _{CC}	2.7					$I_{OH} = -1 \text{ mA}$
		5% V _{CC}	2.7					$I_{OH} = -3 \text{ mA}$
V _{OL}	Output LOW Voltage	10% V _{CC}			0.5	V	Min	I _{OL} = 24 mA
I _{IH}	Input HIGH Current				5.0	μА	Max	V _{IN} = 2.7V
I _{BVI}	Input HIGH Current				7.0	μА	Max	V 7.0V
	Breakdown Test				7.0			$V_{IN} = 7.0V$
I _{CEX}	Output HIGH			50	μΑ	Max	V _{OUT} = V _{CC}	
	Leakage Current			50				
V _{ID}	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu A$
	Test	t				V	0.0	All other pins grounded
I _{OD}	Output Leakage				3.75		0.0	V _{IOD} = 150 mV
	Circuit Current				3.75	μΑ	0.0	All other pins grounded
I _{IL}	Input LOW Current				-0.6	mA	Max	V _{IN} = 0.5V
I _{OZH}	Output Leakage Current				50	μΑ	Max	V _{OUT} = 2.7V
I _{OZL}	Output Leakage Current				-50	μΑ	Max	$V_{OUT} = 0.5V$
Ios	Output Short-Circuit Current		-60		-150	mA	Max	$V_{OUT} = 0V$
I _{ZZ}	Bus Drainage Test				500	μΑ	0.0V	V _{OUT} = 5.25V
I _{CC}	Power Supply Current			65	90	mA	Max	

AC Electrical Characteristics

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = 0$ °C $V_{CC} = C_L = 0$	Units		
		Min	Тур	Max	Min	Max		
t _{PLH}	Propagation Delay	2.5	5.4	8.0	2.0	9.0	no	
t _{PHL}	D _n to O _n	1.5	4.2	6.5	1.5	7.0	ns	
t _{PLH}	Propagation Delay	5.0	8.5	12.0	4.5	13.5	ns	
t _{PHL}	LE to O _n	2.0	4.7	7.5	2.0	8.0		
t _{PLH}	Propagation Delay PRE to On	3.0	7.3	10.0	2.5	11.0	ns	
t _{PHL}	Propagation Delay CLR to On	3.0	6.9	10.0	2.5	11.0	ns	
t _{PZH}	Output Enable Time	2.5	5.0	8.5	2.0	9.5		
t _{PZL}	OE to On	2.5	6.1	9.0	2.0	10.0	ns	
t _{PHZ}	Output Disable Time	1.0	3.6	6.5	1.0	7.5		
t _{PLZ}	OE to O _n	1.0	3.4	6.5	1.0	7.5	ns	

AC Operating Requirements

		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$		Units
Symbol	Parameter					
		Min	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	2.0		2.5		
t _S (L)	D _n to LE	2.0		2.5		ns
t _H (H)	Hold Time, HIGH or LOW	2.5		3.0		115
t _H (L)	D _n to LE	3.0		3.5		
t _W (H)	LE Pulse Width, HIGH	4.0		4.0		ns
t _W (L)	PRE Pulse Width, LOW	5.0		5.0		ns
t _W (L)	CLR Pulse Width, LOW	5.0		5.0		ns
t _{REC}	PRE Recovery Time	10.0		10.0		ns
t _{REC}	CLR Recovery Time	12.0		13.0		ns



24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Package Number M24B

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